74AHC3GU04-Q100

Triple unbuffered inverter Rev. 1 — 18 November 2013

Product data sheet

1. General description

The 74AHC3GU04-Q100 is a high-speed Si-gate CMOS device. This device provides three inverter gates with unbuffered outputs.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - Specified from –40 °C to +85 °C and from –40 °C to +125 °C
- Symmetrical output impedance
- High noise immunity
- Low power dissipation
- Balanced propagation delays
- Multiple package options
- ESD protection:
 - MIL-STD-883, method 3015 exceeds 2000 V
 - HBM JESD22-A114F exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V (C = 200 pf, R = 0 Ω)

Ordering information 3.

Table 1. **Ordering information**

Type number	Package			
	Temperature range	Name	Description	Version
74AHC3GU04DP-Q100	–40 °C to +125 °C	TSSOP8	plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm	SOT505-2
74AHC3GU04DC-Q100	–40 °C to +125 °C	VSSOP8	plastic very thin shrink small outline package; 8 leads; body width 2.3 mm	SOT765-1

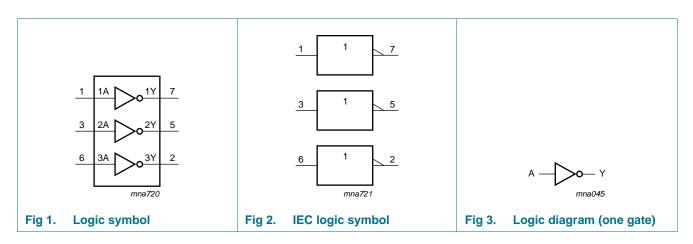


4. Marking

Table 2. Marking codes	
Type number	Marking code ^[1]
74AHC3GU04DP-Q100	AU4
74AHC3GU04DC-Q100	AU4

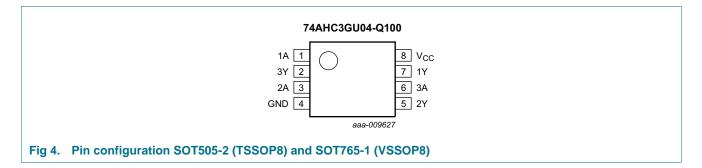
[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

5. Functional diagram



6. Pinning information

6.1 Pinning



6.2 Pin description

Table 3. Pin description						
Symbol	Pin	Description				
1A, 2A, 3A	1, 3, 6	data input				
GND	4	ground (0 V)				
1Y, 2Y, 3Y	7, 5, 2	data output				
V _{CC}	8	supply voltage				

7. Functional description

Table 4. Function table

H = HIGH voltage level; L = LOW voltage level

Input	Output
Α	Y
L	Н
Н	L

8. Limiting values

Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+7.0	V
VI	input voltage		-0.5	+7.0	V
I _{IK}	input clamping current	V _I < -0.5 V	<u>[1]</u> –20	-	mA
I _{OK}	output clamping current	$V_{\rm O}$ < –0.5 V or $V_{\rm O}$ > $V_{\rm CC}$ + 0.5 V	<u>[1]</u> -	±20	mA
lo	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	-	±25	mA
I _{CC}	supply current		-	75	mA
I _{GND}	ground current		-75	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	T_{amb} = -40 °C to +125 °C	[2] _	250	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] For TSSOP8 package: above 55 °C the value of P_{tot} derates linearly with 2.5 mW/K. For VSSOP8 package: above 110 °C the value of P_{tot} derates linearly with 8 mW/K.

9. Recommended operating conditions

Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

•		,				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CC}	supply voltage		2.0	5.0	5.5	V
VI	input voltage		0	-	5.5	V
Vo	output voltage		0	-	V _{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
$\Delta t / \Delta V$	input transition rise and fall rate	V_{CC} = 3.3 V \pm 0.3 V	-	-	100	ns/V
		$V_{CC} = 5.0 \text{ V} \pm 0.5 \text{ V}$	-	-	20	ns/V

10. Static characteristics

Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		–40 °C	to +85 °C	–40 °C to +125 °C		Unit
			Min	Тур	Max	Min	Max	Min	Max	
V _{IH}	HIGH-level	V _{CC} = 2.0 V	1.7	-	-	1.7	-	1.7	-	V
	input voltage	V _{CC} = 3.0 V	2.4	-	-	2.4	-	2.4	-	V
		V _{CC} = 5.5 V	4.4	-	-	4.4	-	4.4	-	V
V _{IL}	LOW-level	V _{CC} = 2.0 V	-	-	0.3	-	0.3	-	0.3	V
	input voltage	V _{CC} = 3.0 V	-	-	0.6	-	0.6	-	0.6	V
		V _{CC} = 5.5 V	-	-	1.1	-	1.1	-	1.1	V
V _{ОН}	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = -50 \ \mu A; \ V_{CC} = 2.0 \ V$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_0 = -50 \ \mu A; \ V_{CC} = 3.0 \ V$	2.9	3.0	-	2.9	-	2.9	-	V
		$I_O = -50 \ \mu\text{A}; \ V_{CC} = 4.5 \ \text{V}$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_0 = -4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.58	-	-	2.48	-	2.40	-	V
		$I_{O} = -8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.94	-	-	3.8	-	3.70	-	V
V _{OL}	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = 50 \ \mu A; \ V_{CC} = 2.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 50 \ \mu A; \ V_{CC} = 3.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 50 \ \mu\text{A}; \ V_{CC} = 4.5 \ \text{V}$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
		$I_0 = 8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
I	input leakage current	V _I = 5.5 V or GND; V _{CC} = 0 V to 5.5 V	-	-	0.1	-	1.0	-	2.0	μΑ
I _{CC}	supply current		-	-	1.0	-	10	-	40	μΑ
Cı	input capacitance		-	3.0	10	-	10	-	10	рF

Table 8.

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11. Dynamic characteristics

Dynamic characteristics

Symbol	Parameter	Conditions	Conditions		25 °C		–40 °C to +85 °C		–40 °C to +125 °C		Unit
				Min	Тур	Max	Min	Max	Min	Max	1
t _{pd} propagation delay	nA to nY; see Figure 5	[1]					1		1		
	$V_{CC} = 3.0 \text{ V} \text{ to } 3.6 \text{ V}$	[2]									
		C _L = 15 pF		-	3.0	7.1	1.0	8.5	1.0	10.0	ns
		C _L = 50 pF		-	4.3	10.6	1.0	12.0	1.0	13.5	ns
		V_{CC} = 4.5 V to 5.5 V	[3]								
		C _L = 15 pF		-	2.5	5.5	1.0	6.0	1.0	7.0	ns
		C _L = 50 pF		-	3.5	7.0	1.0	8.0	1.0	9.0	ns
C _{PD}	power dissipation capacitance	per buffer; $V_I = GND$ to V_{CC}	<u>[4]</u>	-	4	-	-	-	-	-	pF

[1] t_{pd} is the same as t_{PLH} and t_{PHL} .

[2] Typical values are measured at V_{CC} = 3.3 V.

[3] Typical values are measured at V_{CC} = 5.0 V.

[4] C_{PD} is used to determine the dynamic power dissipation (P_D in μ W).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$ where:

 f_i = input frequency in MHz;

 $f_o = output$ frequency in MHz;

 C_L = output load capacitance in pF;

 V_{CC} = supply voltage in V;

N = number of inputs switching;

 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.

12. Waveforms

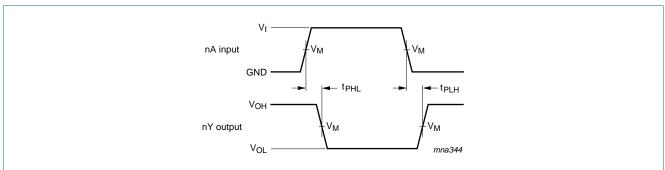


Fig 5. The input (nA) to output (nY) propagation delays.

Table 9. Measurement points

Туре	Input	Output
	V _M	V _M
74AHC3GU04-Q100	0.5V _{CC}	0.5V _{CC}

74AHC3GU04-Q100

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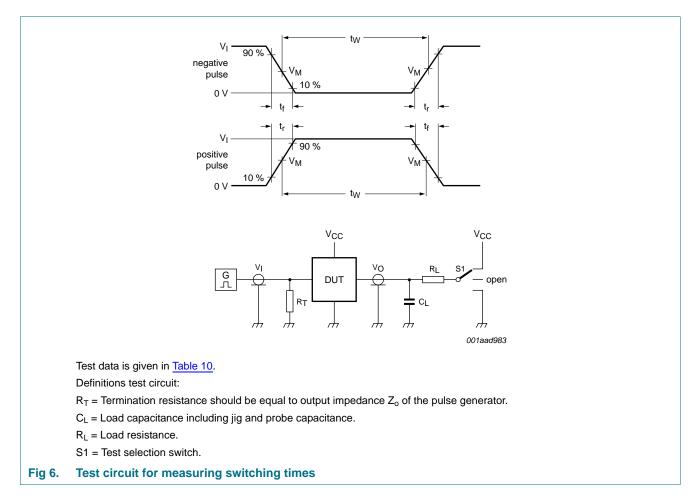
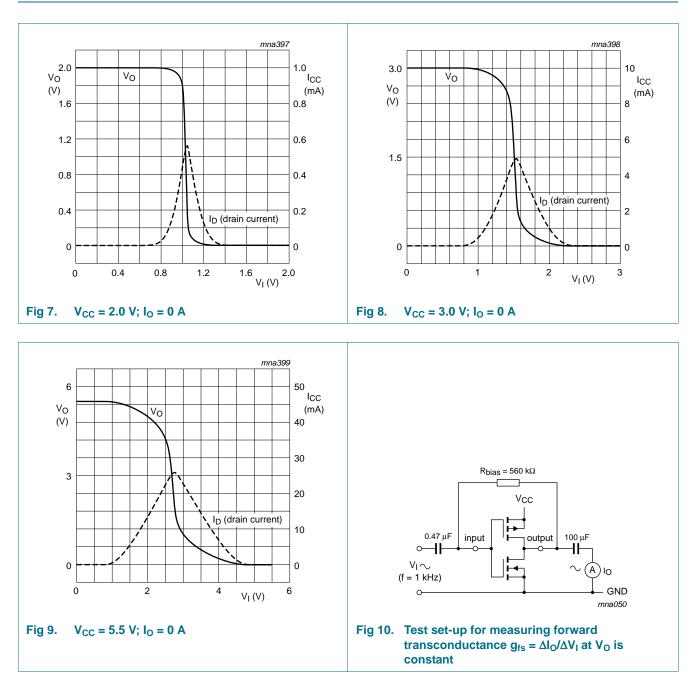


Table 10. Test data

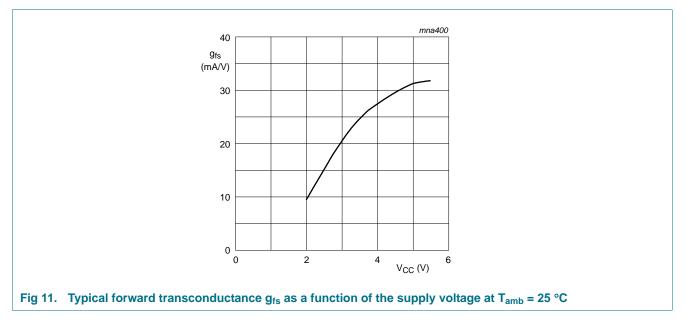
Туре	Input		Load		S1 position		
	VI	t _r , t _f	CL	RL	t _{PHL} , t _{PLH}	t _{PZH} , t _{PHZ}	t _{PZL} , t _{PLZ}
74AHC3GU04-Q100	V _{CC}	\leq 3 ns	15 pF, 50 pF	1 kΩ	open	GND	V _{CC}



13. Typical transfer characteristics

74AHC3GU04_Q100

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14. Application information

Some applications are:

- Linear amplifier (see Figure 12)
- Crystal oscillator design (see Figure 13)

Remark: All values given are typical unless otherwise specified.

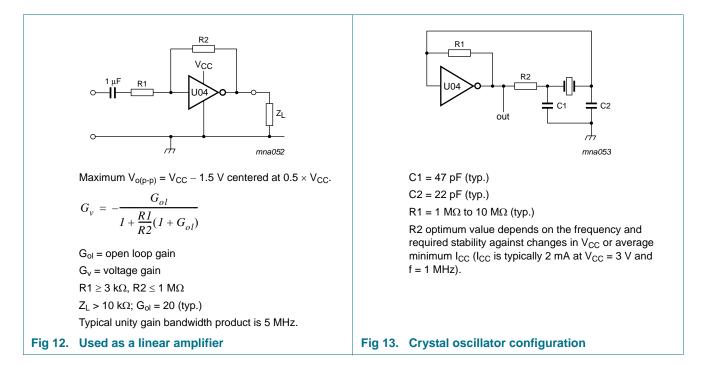


Table 11. External components for resonator (f < 1 MHz)</th>

All values given are typical and must be used as an initial set-up.

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Frequency	R1	R2	C1	C2
10 kHz to 15.9 kHz	22 M Ω	220 kΩ	56 pF	20 pF
16 kHz to 24.9 kHz	22 Μ Ω	220 kΩ	56 pF	10 pF
25 kHz to 54.9 kHz	22 Μ Ω	100 kΩ	56 pF	10 pF
55 kHz to 129.9 kHz	22 Μ Ω	100 kΩ	47 pF	5 pF
130 kHz to 199.9 kHz	22 Μ Ω	47 kΩ	47 pF	5 pF
200 kHz to 349.9 kHz	22 Μ Ω	47 kΩ	47 pF	5 pF
350 kHz to 600 kHz	22 Μ Ω	47 kΩ	47 pF	5 pF

Table 12.Optimum value for R2

Frequency	R2	Optimum for
3 kHz	2.0 kΩ	minimum required I _{CC}
	8.0 kΩ	minimum influence due to change in V _{CC}
6 kHz	1.0 kΩ	minimum required I _{CC}
	4.7 kΩ	minimum influence by V _{CC}
10 kHz	0.5 kΩ	minimum required I _{CC}
	2.0 kΩ	minimum influence by V _{CC}
14 kHz	0.5 kΩ	minimum required I _{CC}
	1.0 kΩ	minimum influence by V _{CC}
>14 kHz	-	replace R2 by C3 with a typical value of 35 pF

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15. Package outline

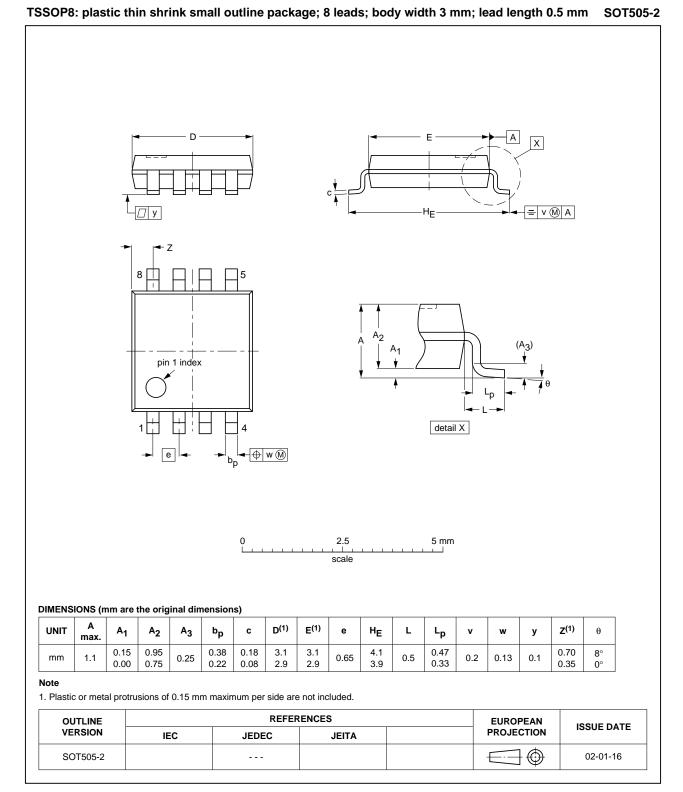


Fig 14. Package outline SOT505-2 (TSSOP8)

74AHC3GU04_Q100

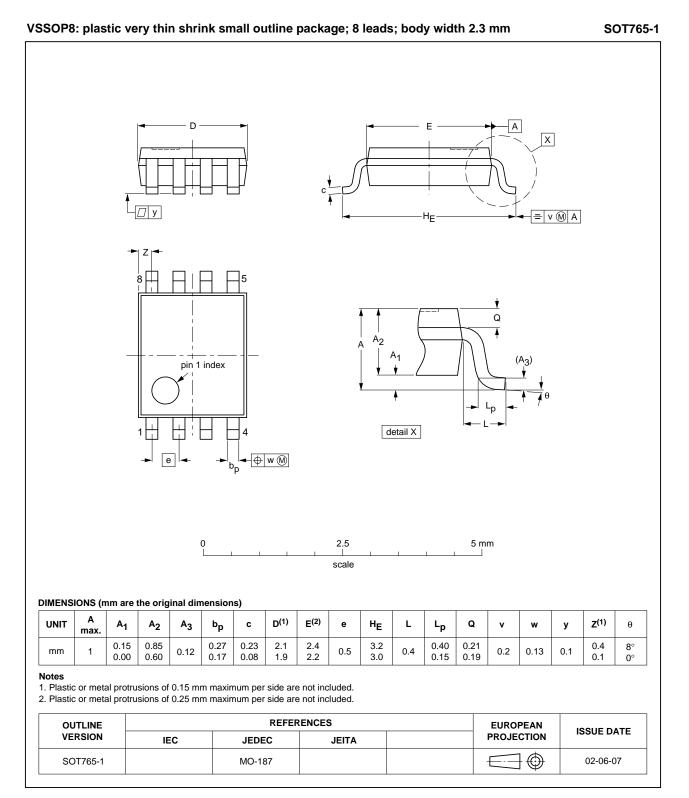


Fig 15. Package outline SOT765-1 (VSSOP8)

74AHC3GU04_Q100

16. Abbreviations

AcronymDescriptionCDMCharged Device ModelCMOSComplementary Metal-Oxide SemiconductorDUTDevice Under TestESDElectroStatic DischargeHBMHuman Body ModelMILMilitary	Table 13. Abbreviations						
CMOSComplementary Metal-Oxide SemiconductorDUTDevice Under TestESDElectroStatic DischargeHBMHuman Body Model		I	I			D	escription
DUTDevice Under TestESDElectroStatic DischargeHBMHuman Body Model						C	harged Device Model
ESD ElectroStatic Discharge HBM Human Body Model						C	omplementary Metal-Oxide Semiconductor
HBM Human Body Model						D	evice Under Test
						EI	lectroStatic Discharge
MIL Military						H	uman Body Model
						М	ilitary
MM Machine Model						М	achine Model

17. Revision history

Table 14. Revision history								
Document ID	Release date	Data sheet status	Change notice	Supersedes				
74AHC3GU04_Q100 v.1	20131118	Product data sheet	-	-				

18. Legal information

18.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Product data sheet

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